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PUBLICATION FONDAMENTALE EN CEM

**Specification for radio disturbance and immunity measuring apparatus and methods –
Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements**

**Spécifications des méthodes et des appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques –
Partie 1-2: Appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques – Dispositifs de couplage pour la mesure des perturbations conduites**



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CONTENTS

FOREWORD.....	7
1 Scope.....	9
2 Normative references	9
3 Terms, definitions and abbreviations	10
3.1 Terms and definitions.....	10
3.2 Abbreviations.....	12
4 Artificial mains networks.....	12
4.1 General.....	12
4.2 AMN impedance.....	12
4.3 50 Ω/50 μH + 5 Ω artificial mains V-network (V-AMN) for use in the frequency range 9 kHz to 150 kHz	13
4.4 50 Ω/50 μH artificial mains V-network (V-AMN) for use in the frequency range 0,15 MHz to 30 MHz	14
4.5 50 Ω/5 μH + 1 Ω artificial mains V-network (V-AMN) for use in the frequency range 150 kHz to 108 MHz	15
4.6 150 Ω artificial mains V-network (V-AMN) for use in the frequency range 150 kHz to 30 MHz	17
4.7 150 Ω artificial mains delta-network (Δ-AMN) for use in the frequency range 150 kHz to 30 MHz.....	17
4.7.1 General parameters	17
4.7.2 Balance of the 150 Ω artificial mains delta-network.....	17
4.8 Isolation.....	18
4.8.1 Requirement.....	18
4.8.2 Measurement procedure	18
4.9 Current carrying capacity and series voltage drop.....	19
4.10 Modified reference ground connection	19
4.11 Measurement of the voltage division factor of artificial mains V-networks.....	20
5 Current and voltage probes	21
5.1 Current probes.....	21
5.1.1 General	21
5.1.2 Construction	21
5.1.3 Characteristics.....	21
5.2 Voltage probe	22
5.2.1 High impedance voltage probe.....	22
5.2.2 Capacitive voltage probe	23
6 Coupling units for conducted current immunity measurement	25
6.1 General.....	25
6.2 Characteristics.....	25
6.2.1 General	25
6.2.2 Impedance.....	25
6.2.3 Insertion loss	25
7 Coupling devices for measuring signal lines	26
7.1 General.....	26
7.2 Requirements for AANs (or Y-networks).....	26
7.3 Requirements for artificial networks for coaxial and other screened cables.....	30
8 The artificial hand and series RC element	30

8.1	General.....	30
8.2	Construction of the artificial hand and RC element.....	30
8.3	The use of the artificial hand.....	31
9	CDNE for measurement of disturbance voltage in frequency range 30 MHz to 300 MHz.....	34
9.1	Instrumentation.....	34
9.1.1	General.....	34
9.1.2	Description of the CDNE measurement.....	35
9.1.3	Description of the RGP.....	35
9.2	Technical requirements for the CDNE-X.....	36
9.2.1	Mechanical and electrical parameters.....	36
9.2.2	Validation of the CDNE.....	36
9.3	Technical requirement for the RGP.....	39
Annex A	(normative) AMNs.....	40
A.1	General.....	40
A.2	An example of the 50 Ω /50 μ H + 5 Ω artificial mains V-network.....	40
A.3	An example of the 50 Ω /50 μ H artificial mains V-network.....	41
A.4	Examples of the 50 Ω /5 μ H + 1 Ω artificial mains V-network.....	41
A.5	An example of the 150 Ω artificial mains V-network.....	42
A.6	Example of the 150 Ω artificial mains delta-network.....	43
A.7	Example design for an AMN with a 50 μ H inductor.....	44
A.7.1	The inductor.....	44
A.7.2	The case of the inductor.....	45
A.7.3	Isolation of the inductor.....	46
A.8	Measurement of the voltage division factor of an artificial mains V-network.....	46
Annex B	(informative) Construction, frequency range, and calibration of current probes.....	49
B.1	Physical and electrical considerations for current probes.....	49
B.2	Equivalent electrical circuit of current probe.....	51
B.3	Detrimental effects of current probe measurements.....	51
B.4	Typical frequency response characteristics of current probes.....	52
B.5	A shielding structure for use with current probes.....	53
B.5.1	General.....	53
B.5.2	Theoretical model.....	54
B.5.3	Construction of the shielding structure.....	55
B.5.4	High-pass filter.....	55
B.6	Calibration of current probes.....	55
Annex C	(informative) Construction of the coupling units for current injection for the frequency range 0,15 MHz to 30 MHz.....	59
C.1	Coupling unit type A for coaxial antenna input.....	59
C.2	Coupling unit type M, for mains leads.....	59
C.3	Coupling unit type L, for loudspeaker leads.....	62
C.4	Coupling unit type Sw, for audio-frequency signals.....	63
C.5	Coupling unit type Sw, for audio, video, and control signals.....	63
Annex D	(informative) Principle of operation and examples of coupling units for conducted current immunity measurements.....	65
D.1	Principle of operation.....	65
D.2	Types of unit and their construction.....	65

Annex E (normative) Example and measurement of the parameters of the asymmetric artificial network (AAN) 69

 E.1 Description of an example of an AAN: the T-network..... 69

 E.2 Measurements of the parameters of an asymmetric artificial network (AAN) 69

Annex F (normative) Example and measurement of the parameters of the AN for coaxial and other screened cables..... 75

 F.1 Description of ANs for coaxial and other screened cables 75

 F.2 Measurements of parameters of an AN for coaxial and other screened cables..... 75

Annex G (informative) Construction and evaluation of capacitive voltage probe 77

 G.1 General..... 77

 G.2 Physical and electrical considerations for CVP..... 77

 G.3 Determination of the frequency response of the voltage division factor 77

 G.4 Method of measurement to determine the influence of external electric fields..... 78

 G.4.1 Influence of external electric field 78

 G.4.2 Method of measurement to determine the influence of the external electric field 78

 G.5 Pulse response 78

 G.6 Voltage division factor dependence..... 79

Annex H (informative) Rationale for the introduction of a minimum decoupling factor between mains and EUT/receiver ports for the V-AMN..... 84

Annex I (informative) Rationale for the introduction of a phase tolerance for the V-AMN input impedance..... 85

Annex J (informative) Example CDNE set-up diagrams 87

 J.1 CDNE-M2 and CDNE-M3 87

 J.2 CDNE-S_x 89

Bibliography..... 90

Figure 1 – Impedance (magnitude and phase) of the V-network for Band A (see 4.3, the relevant frequency range is from 9 kHz to 150 kHz) 16

Figure 2 – Impedance (magnitude and phase) of the V-network for Band B (see 4.4)..... 16

Figure 3 – Impedance (magnitude and phase) of the V-network for Bands B and C (from 150 kHz to 108 MHz; see 4.5)..... 17

Figure 4 – Method for checking the balance of the arrangement for the measurement of symmetrical voltages 18

Figure 5 – Example of artificial mains 50 Ω/50 μH + 5 Ω V-network (see 4.3 and A.2)..... 20

Figure 6 – Example of artificial mains V-networks, 50 Ω/50 μH, 50 Ω /5 μH + 1 Ω or 150 Ω (see 4.4, 4.5, 4.6, A.3, A.4 and A.5, respectively) 20

Figure 7 – Circuit for RF voltage measurement on supply mains 23

Figure 8 – Circuit used to make voltage measurements between a cable and reference ground 24

Figure 9 – Measuring set-up to check the insertion loss of the coupling units in the frequency range 30 MHz to 150 MHz 26

Figure 10 – Principal circuit and LCL requirements of an AAN 28

Figure 11 – Application of the artificial hand 33

Figure 12 – Examples of application of artificial hand to ITE 34

Figure 13 – Arrangement for validation of a CDNE..... 37

Figure 14 – IMA arrangement for correcting the electrical length.....	38
Figure 15 – Test arrangement for the measurement of the symmetric impedance (Z_{DM}).....	39
Figure A.1 – Example of an alternative 50 Ω /5 μ H + 1 Ω V-AMN for devices used with low impedance power sources	42
Figure A.2 – Example of a Δ -AMN for a measuring receiver with unbalanced input	43
Figure A.3 – Schematic of 50 μ H inductor	45
Figure A.4 – General view of an AMN	45
Figure A.5 – Attenuation of an AMN filter	46
Figure A.6 – Test set-up for determining the voltage division factor	47
Figure B.1 – Typical current probe configuration	50
Figure B.2 – High-pass filter with cut-off frequency of 9 kHz	52
Figure B.3 – Transfer impedance of typical current probes.....	53
Figure B.4 – Set-up for current measurement using the AMN.....	54
Figure B.5 – Shield configuration used with current transformer.....	55
Figure B.6 – Schematic diagram of circuit with coaxial adaptor and current probe transfer admittance Y_T measurement.....	56
Figure B.7 – Transfer admittance Y_T as a function of frequency.....	57
Figure B.8 – Return loss of the coaxial adaptor terminated with 50 Ω and with the current probe (also terminated with 50 Ω) inside	57
Figure B.9 – Current probe between the two halves of the coaxial adaptor.....	58
Figure C.1 – Example of coupling unit type A, for coaxial input schematic diagram and construction details (see C.1 and D.2)	60
Figure C.2 – Example of coupling unit type M, for mains leads, schematic diagram and construction details (see C.2 and D.2)	61
Figure C.3 – Example of coupling unit type L for loudspeaker leads, schematic diagram and simplified construction drawing (see D.2)	62
Figure C.4 – Example of coupling unit type Sw, for audio signals. Schematic diagram and simplified construction drawing (see D.2)	63
Figure C.5 – Example of coupling unit type Sw, for audio, video and control signals, schematic diagram and simplified construction drawing (see D.2)	64
Figure D.1 – General principle of the current-injection method (see D.1).....	67
Figure D.2 – Coupling unit type Sr with load resistances – Schematic diagram and simplified construction drawing (see D.2).....	68
Figure E.1 – Example of a T-network circuit for one pair of wires	70
Figure E.2 – Arrangement for the termination impedance measurement.....	71
Figure E.3 – Arrangement for LCL probe verification.....	71
Figure E.4 – Arrangement for the LCL probe calibration using an L-circuit	72
Figure E.5 – LCL measurement of the AAN using an LCL probe	72
Figure E.6 – Test set-up for the decoupling attenuation (isolation) of the AAN	
$a_{\text{decoup}} = 20 \lg \left \frac{V_1}{V_2} \right - a_{\text{vdiv}}$ in dB for asymmetric signals between AE port and EUT port	73
Figure E.7 – Test set-up for the insertion loss (symmetric) of the AAN.....	73
Figure E.8 – Calibration test set-up for the AAN voltage division factor of the asymmetric circuit: $F_{\text{AAN}} = a_{\text{vdiv}} = 20 \lg \left \frac{V_1}{V_2} \right $ in dB	74
Figure F.1 – Example of a coaxial cable AN.....	75

Figure F.2 – Test set-up for the coaxial and screened cable AN voltage division factor
 $F_{AN} = 20 \lg \left| \frac{V_1}{V_2} \right|$ in dB..... 76

Figure G.1 – Configuration of a CVP 80

Figure G.2 – Equivalent circuit of a CVP 81

Figure G.3 – Test set-up to measure the frequency response 81

Figure G.4 – Electrostatic coupling model and its equivalent circuit 82

Figure G.5 – Test set-up to measure the reduction, through the shielding effect, of the influence of the external electric field caused by electrostatic coupling 82

Figure G.6 – Conversion factor deviation when cable position is changed..... 83

Figure G.7 – Investigation result of the cable radius dependence..... 83

Figure H.1 – Isolation measurement arrangement 84

Figure I.1 – Definition of impedance magnitude and phase tolerances 85

Figure J.1 – CDNE-M3 with internal attenuator a_{meas} of at least 6 dB..... 87

Figure J.2 – CDNE-M2 with internal attenuator a_{meas} of at least 6 dB..... 88

Figure J.3 – CDNE- S_x for screened cable with x internal wires and an internal attenuator of at least 6 dB..... 89

Table 1 – Magnitudes and phase angles of the V-network (see Figure 1) 13

Table 2 – Magnitudes and phase angles of the V-network (see Figure 2) 14

Table 3 – Magnitudes and phase angles of the V-network (see Figure 3) 15

Table 4 – Values of minimum isolation for V-networks 18

Table 5 – Characteristics of the AAN for the measurement of asymmetric disturbance voltage..... 29

Table 6 – Characteristics of artificial networks for coaxial and other screened cables 30

Table 7 – Electrical parameters of the CDNE- X 36

Table A.1 – Component values of $50 \Omega/50 \mu\text{H} + 5 \Omega$ V-network 40

Table A.2 – Component values of $50 \Omega/50 \mu\text{H}$ V-network 41

Table A.3 – Component values of $50 \Omega/5 \mu\text{H} + 1 \Omega$ V-network 42

Table A.4 – Component values of the 150Ω V-network 43

Table A.5 – Component values of the 150Ω delta-network 44

INTERNATIONAL ELECTROTECHNICAL COMMISSION
INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

**SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY
MEASURING APPARATUS AND METHODS –**

**Part 1-2: Radio disturbance and immunity measuring apparatus –
Coupling devices for conducted disturbance measurements**

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International Standard CISPR 16-1-2 has been prepared by subcommittee A: Radio-interference measurements and statistical methods, of IEC technical committee CISPR: International special committee on radio interference.

This second edition cancels and replaces the first edition published in 2003 and its Amendment 1 (2004) and Amendment 2 (2006). This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) requirements from CISPR 22 for the AAN have been copied to this standard;
- b) the CDNE for measurement of disturbance voltage in the frequency range 30 MHz to 300 MHz is added;
- c) additional maintenance is included.

It has the status of a basic EMC publication in accordance with IEC Guide 107, *Electromagnetic compatibility – Guide to the drafting of electromagnetic compatibility publications*.

The text of this standard is based on the following documents:

FDIS	Report on voting
CISPR/A/1051/FDIS	CISPR/A/1059/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all parts of CISPR 16 series, under the general title *Specification for radio disturbance and immunity measuring apparatus and methods*, can be found on the IEC website.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements

1 Scope

This part of the CISPR 16 series specifies the characteristics and performance of equipment for the measurement of radio disturbance voltages and currents in the frequency range 9 kHz to 1 GHz.

NOTE In accordance with IEC Guide 107, CISPR 16 is a basic EMC standard for use by product committees of the IEC. As stated in Guide 107, product committees are responsible for determining the applicability of the EMC standard. CISPR and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular EMC tests for specific products.

Specifications for ancillary apparatus are included for artificial mains networks, current and voltage probes and coupling units for current injection on cables.

It is intended that the requirements of this publication are fulfilled at all frequencies and for all levels of radio disturbance voltages and currents within the CISPR indicating range of the measuring equipment.

Methods of measurement are covered in the CISPR 16-2 series, and further information on radio disturbance is given in CISPR 16-3, while uncertainties, statistics and limit modelling are covered in the CISPR 16-4 series.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 16-1-1:2010, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-1: Radio disturbance and immunity measuring apparatus – Measuring apparatus*

CISPR 16-2-1:2014, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements*

CISPR 16-4-2:2011, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Measurement instrumentation uncertainty*

IEC 60050 (all parts), *International Electrotechnical Vocabulary* (available at <<http://www.electropedia.org>>)

IEC 61000-4-6:2008, *Electromagnetic compatibility (EMC) – Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields*